

P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
- 60	0.0160at V _{GS} = - 10 V	- 53	76 nC			
- 60	0.0200 at V _{GS} = - 4.5 V	- 42	70110			

FEATURES

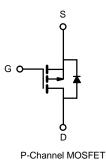
- TrenchFET® Power MOSFET
- 100 % UIS Tested

APPLICATIONS

Load Switch







ABSOLUTE MAXIMUM RATINGS	S (T _A = 25 °C, unle	ss otherwise not	ed)	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 60	V	
Gate-Source Voltage	V _{GS}	± 20	v	
	T _C = 25 °C		- 53 ^a	
Continuous Proin Current /T 450 °C)	T _C = 70 °C		- 46.8	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	9.2 ^b	_
	T _A = 70 °C		- 8.1 ^b	A
Pulsed Drain Current	I _{DM}	- 150		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	- 45	
Single Pulse Avalanche Energy	L=0.1 mn	E _{AS}	101	mJ
Continuous Course Brain Binds Correct	T _C = 25 °C	,	69 ^a	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.1 ^b	A
	T _C = 25 °C		104.2 ^a	
Manianum Danian Dinain atian	T _C = 70 °C	В	66.7 ^a	W
Maximum Power Dissipation	T _A = 25 °C	P _D	3.1 ^b	VV
	T _A = 70 °C		2 ^b	
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R_{thJA}	33	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.98	1.2	- "C/VV	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 60			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	1 - 250 uA		68		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = - 250 μA		- 5.2		IIIV/	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1		- 3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zara Cata Valtaga Drain Current	I _{DSS}	V _{DS} = - 60 V, V _{GS} = 0 V			- 1	μA	
Zero Gate Voltage Drain Current		V _{DS} = - 60 V, V _{GS} = 0 V, T _J = 55 °C			- 10		
On-State Drain Current ^a	I _{D(on)}	V _{DS} = - 5 V, V _{GS} = - 10 V	- 120			Α	
D : 0	В	V _{GS} = - 10 V, I _D = - 30 A		0.0160	160		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, I_D = -20 \text{ A}$	0.0200			Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 50 A	20			S	
Dynamic ^b						,	
Input Capacitance	C _{iss}			3500		pF	
Output Capacitance	C _{oss}	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		390			
Reverse Transfer Capacitance	C _{rss}			290			
Total Gata Chargo	Qg	$V_{DS} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -55 \text{ A}$		76	115	nC	
Total Gate Charge				38	60		
Gate-Source Charge	Q_{gs}	$V_{DS} = -30 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -55 \text{ A}$		16			
Gate-Drain Charge	Q_{gd}			19			
Gate Resistance	R_g	f = 1 MHz		5.2		Ω	
Turn-On Delay Time	t _{d(on)}			10	15		
Rise Time	t _r	V_{DD} = - 2 V, R_L = 2 Ω		7	15	ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		70	110		
Fall Time	t _f			40	60		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			- 69	Α	
Pulse Diode Forward Current ^a	I _{SM}				- 150		
Body Diode Voltage	V _{SD}	I _S = - 30 A		- 1	- 1.5	V	
Body Diode Reverse Recovery Time	t _{rr}			45	68	ns	
Sody Diode Reverse Recovery Charge Q _{rr}		L = -50 A di/dt = 100 A/us T = 25 °C		59	120	nC	
Reverse Recovery Fall Time	t _a	$I_F = -50 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		29			
Reverse Recovery Rise Time t _b			16			ns	

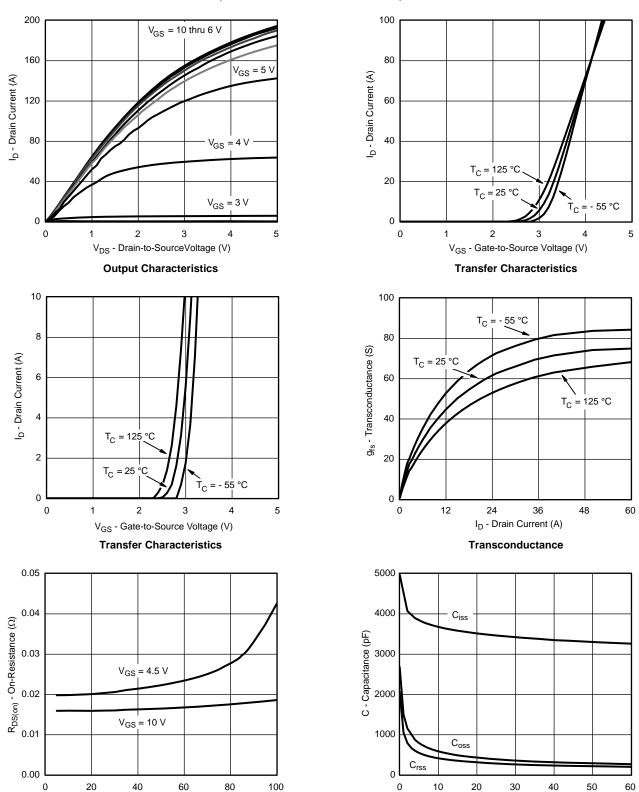
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



服务热线:400-655-8788

I_D - Drain Current (A)

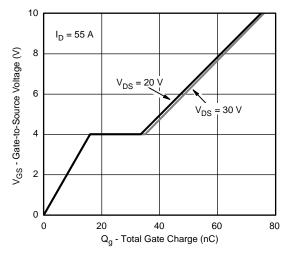
On-Resistance vs. Drain Current

V_{DS} - Drain-to-Source Voltage (V)

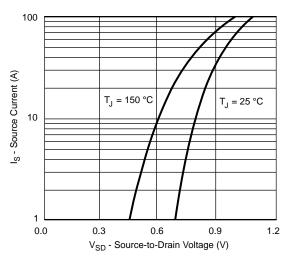
Capacitance



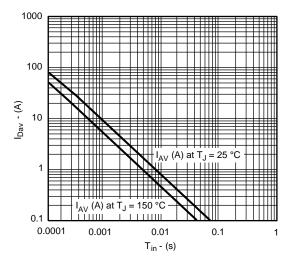
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



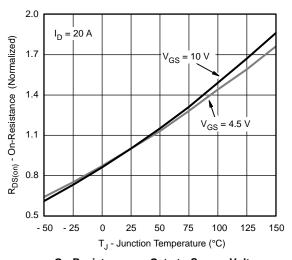
Gate Charge



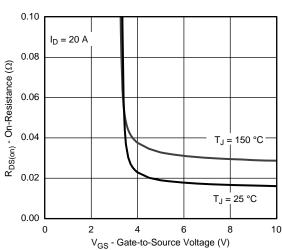
Source-Drain Diode Forward Voltage



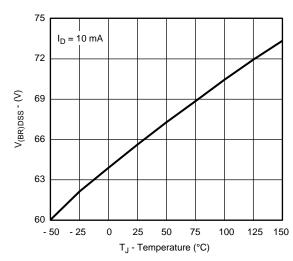
Single Pulse Avalanche Current Capability vs. Time



On-Resistance vs. Gate-to-Source Voltage



On-Resistance vs. Gate-to-Source Voltage



Drain-Source Breakdown Voltage vs. Junction Temperature

20

0

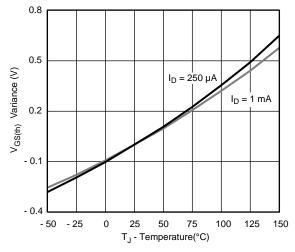
0

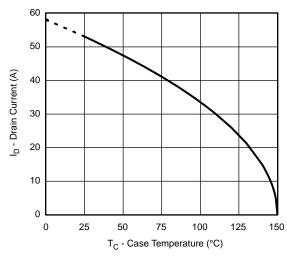
25

50

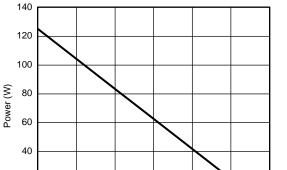


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

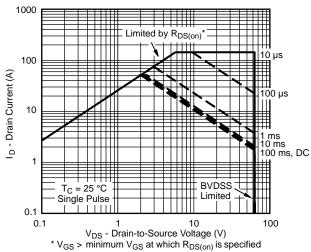




Threshold Voltage



Max. Drain Current vs. Case Temperature



$\label{eq:TJ-Temperature CC} \textbf{Power Derating, Junction-to-Case}$

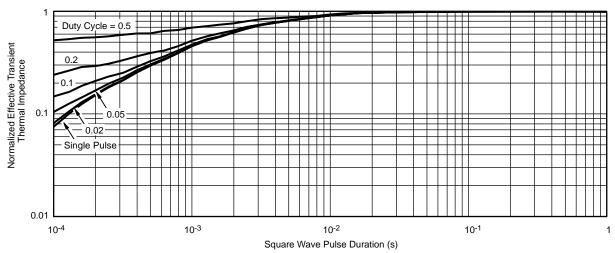
75

100

125

150

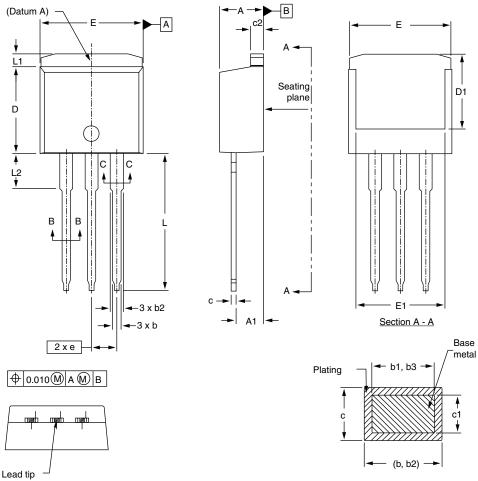




Normalized Thermal Transient Impedance, Junction-to-Case



I²PAK (TO-262) (HIGH VOLTAGE)



INCHES MILLIMETERS DIM. MIN. MAX. MIN. MAX. 4.06 4.83 0.190 Α 0.160 Α1 2.03 3.02 0.080 0.119 b 0.51 0.99 0.020 0.039 b1 0.51 0.89 0.020 0.035 b2 1.14 1.78 0.045 0.070 b3 1.14 1.73 0.045 0.068 0.38 0.74 0.015 0.029 С с1 0.38 0.58 0.015 0.023 c2 1.14 1.65 0.045 0.065

	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
D	8.38	9.65	0.330	0.380	
D1	6.86	-	0.270	-	
Е	9.65	10.67	0.380	0.420	
E1	6.22	-	0.245	-	
е	2.54 BSC		0.100 BSC		
L	13.46	14.10	0.530	0.555	
L1	-	1.65	-	0.065	
L2	3.56	3.71	0.140	0.146	

Section B - B and C - C Scale: None

ECN: S-82442-Rev. A, 27-Oct-08

DWG: 5977

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm per side. These dimensions are measured at the outmost extremes of the plastic body.
- 3. Thermal pad contour optional within dimension E, L1, D1, and E1.
- 4. Dimension b1 and c1 apply to base metal only.



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